Search Notes

Application/Control No.	Applicant(s)/Patent und Reexamination	ler
10/773,554	WU ET AL.	
Examiner	Art Unit	
Hai I Mauyen	2816	

SEARCHED					
Class	Subclass	Date	Examiner		
327	172-176, 97,180	3/10/2005	HLN		
327	50-52				
327	63-65	1	,		
327	100,104	V	V		
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INTERFERENCE SEARCHED				
Subclass	Date	Examiner		
Above	3/13/2005	HLN		
	Subclass	Subclass Date		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Shepardize Search	3/12/2005	HLN		
EAST Text Search "(cross ADJ coupled) ADJ buffer"	3/13/2005	HLN		
EAST Text Search "(duty ADJ (cycle OR ratio)) and (differential WITH (sinusoidal OR (sine ADJ wave)))"	3/13/2005	HLN		
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